Progress and Testing Challenges of Large-aperture Digital Phased Array

Speaker:

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Tron Future Tech Inc.



About Us:

>20% employee with Ph.D. degrees from Caltech/USC/MIT/UCLA/NTU/NCTU/NTHU etc.

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Our Mission:

• We help our customers collect, analyze and utilize valuable data through fundamental sensor and communication inventions.

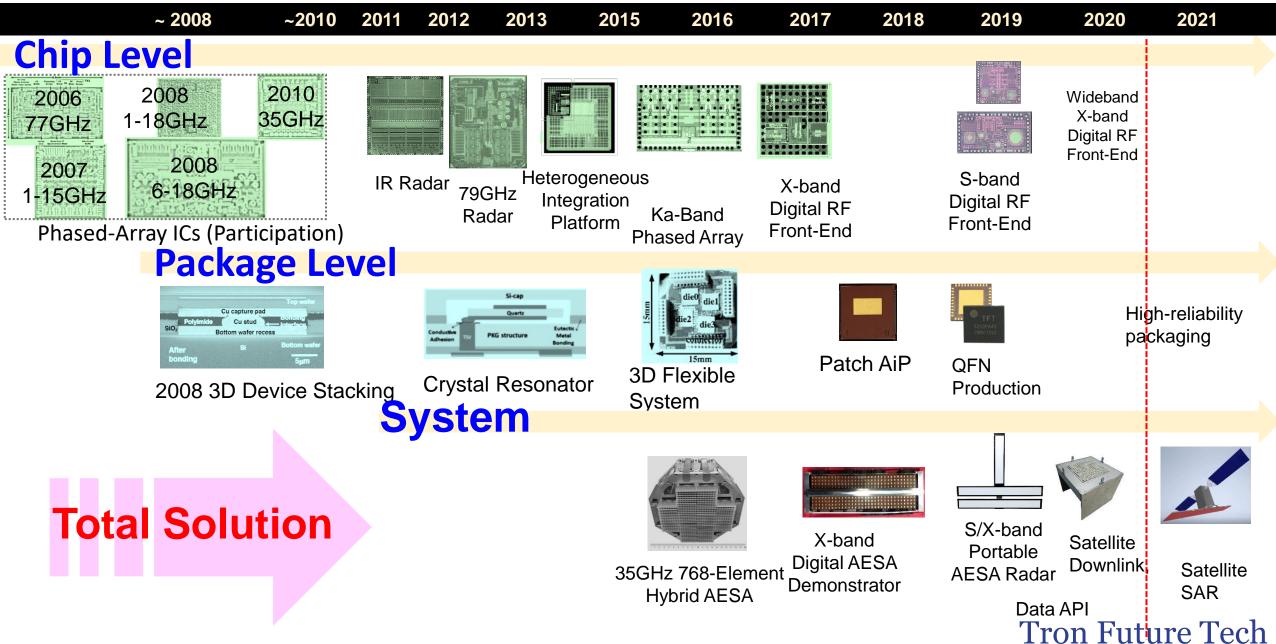
Area of Focus:

- Ultrathin all-digital/hybrid phased array based radar/communication turnkey systems.
- Value-added data processing infrastructure.

Major Capabilities:

- IC design: III/V RFFE, CMOS RFSoC, ASIC
- Module design: Power, FPGA, GPU modules
- Hardware system design: SatCom, AESA Radar
- Software system design: cloud service Tron Future Tech

Our History and Experiences



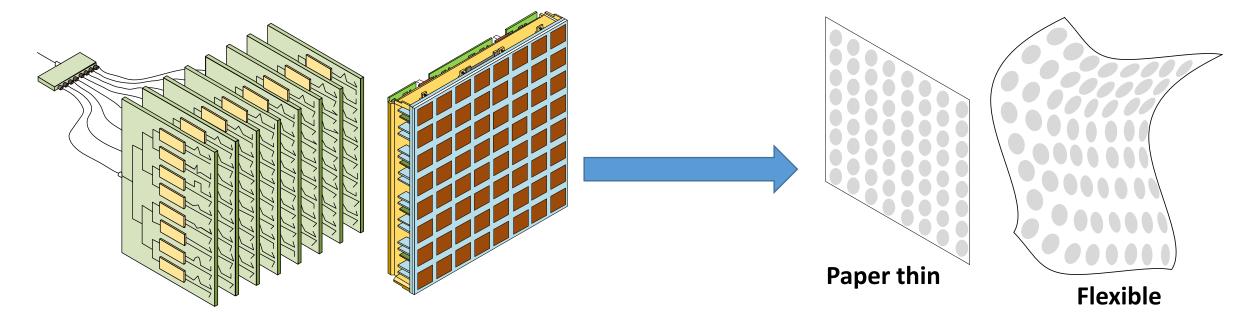
Agenda

- Technology Progress Overview.
- Market Segmentation.
- Testing Challenges.



Let's Imagine Future AESA

(and ignoring technological feasibility for 30 seconds....)



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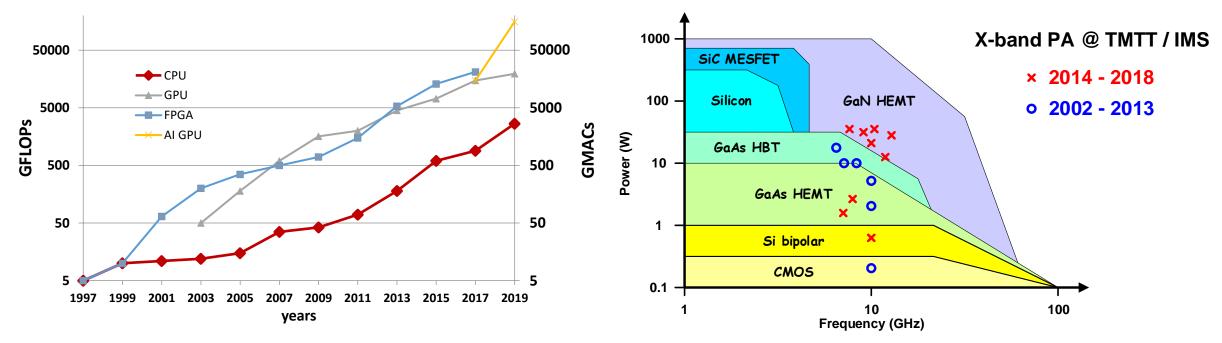
- 1. Paper thin, and probably flexible.
- 2. Include all Radar/COM/EW functions and very easy to use.

Two fundamental problems need to be addressed:

- 1. To what extent can this ideal concept be fundamentally possible?
- 2. How feasible are the underlying technologies today?

Ref: Our 2019 IEEE Radar Talk: An X-band Scalable 4×4 Digital Phased Array Module using RF SoC and Antenna-in-Package

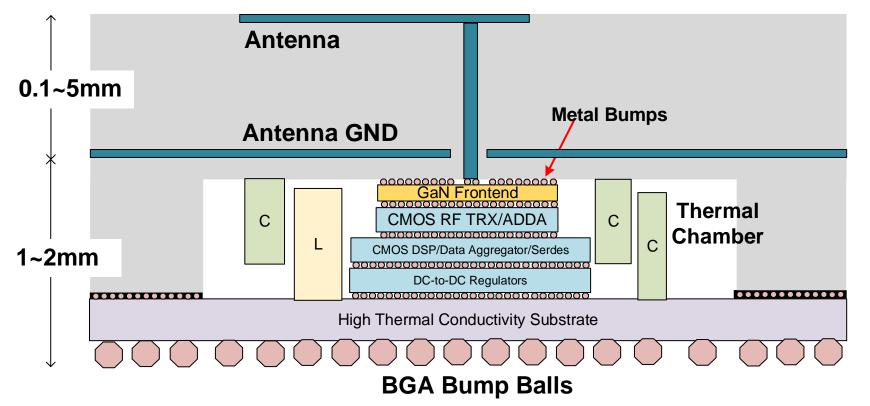
Underlining Technology Progress



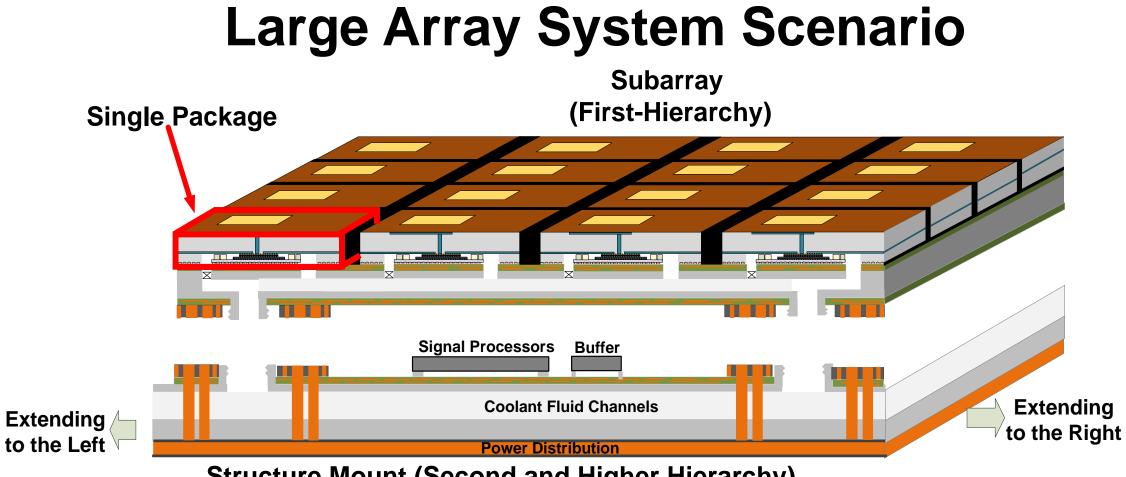
- What breakthroughs have been made in technology?
 - 1. Arithmetic and Logic Circuit → 80x size & performance improvement in last 12 years.
 - **2.** Analog-to-Digital Converter \rightarrow 5x size & power improvement in 10 years.
 - 3. RF Power Amplifier \rightarrow GaN PA generates 10x more power with >50% efficiency.
 - 4. Transceiver Modules \rightarrow discrete to integrated TR module, >100 times size reduction.
 - 5. Packaging and Assembling → 3D-IC-stacking ball grid array (BGA) with flipchip process.

Ref: Our EW Europe 2018 Talk:" Flexibility and Thinness – How Semiconductor Technologies Shape Future Radar and Electronic Warfare?"

A Possible Future X-band Array Element



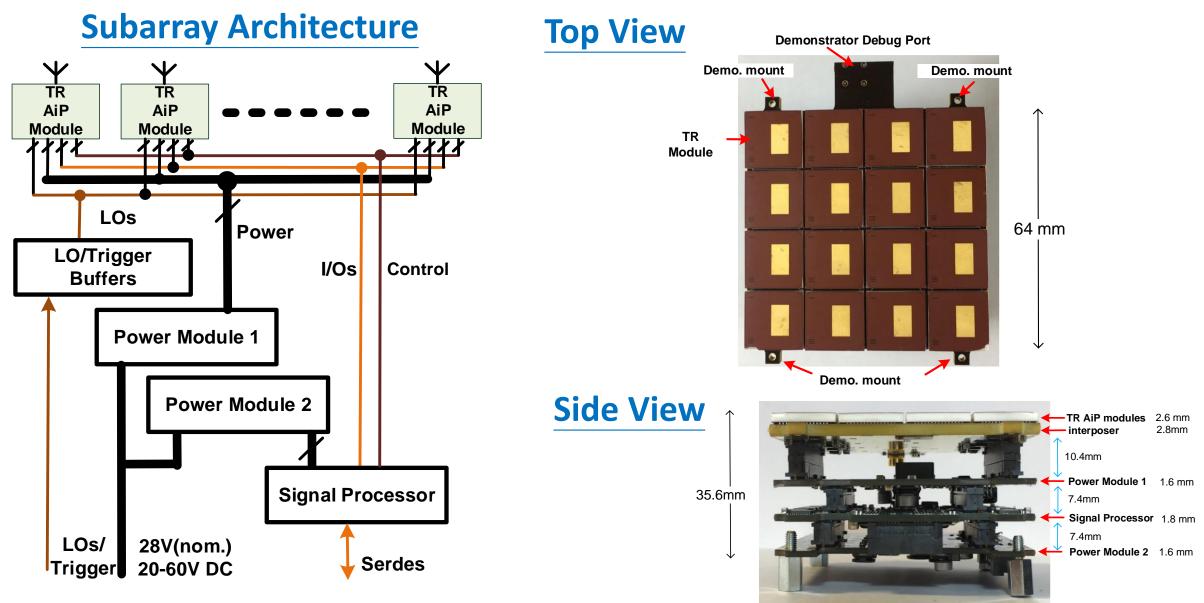
- Antenna is fundamentally limited by (signal wavelength) times (fractional bandwidth) ~ $\left(\lambda_0 \cdot \frac{\Delta f}{f_c}\right)$.
- Electronics will be limited by capacitors, inductors and filters (→ switching speed & material properties).
- Element-level functions will be 3D heterogeneously integrated/packaged. Several challenges:
 - Mechanical stress, and heat exchange.
- The package has to be mounted on a substrate (AIN or graphene on Si/SiC) with a thickness of 300-500
 μm to provide mechanical strength.
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Structure Mount (Second and Higher Hierarchy)

- The thickness is mainly limited by how heat and DC power are transferred.
- For 10GHz system, 3-15 mm subarray thickness and 2-15 mm global mounting structure (secondary or higher hierarchy) can be achieved.
- This make it possible to achieve ~3mm lower-power hundred-element array at X-band, <30mm thickness for THAAD-grade radar within a decade. Tron Future Tech

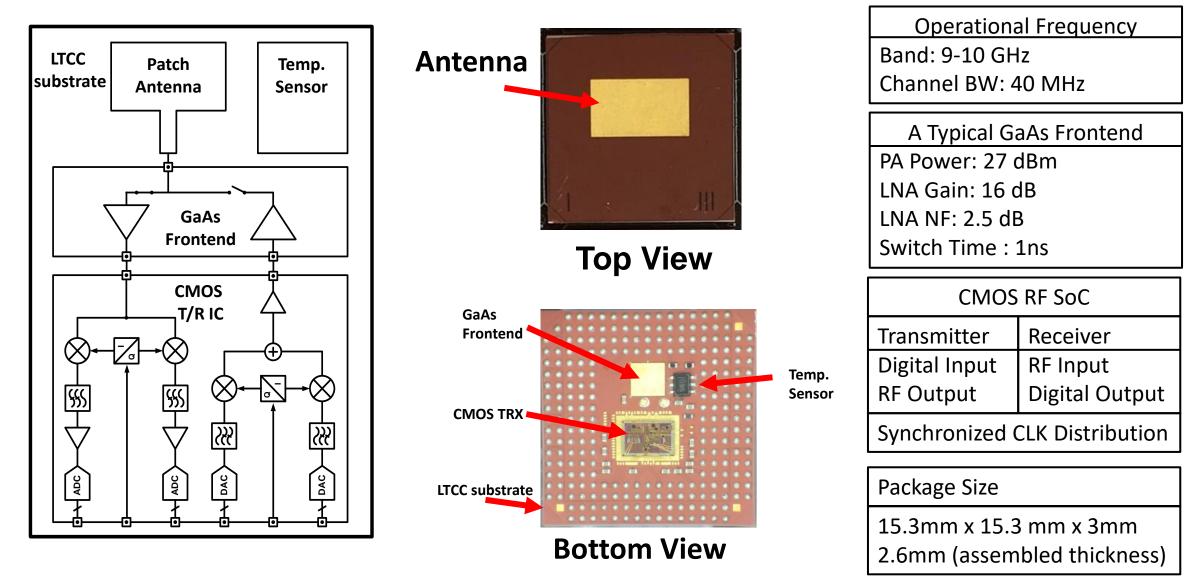
Scalable Subarray 2018 Prototype (4x4)



• Element-level digital AESA with cm-thickness.

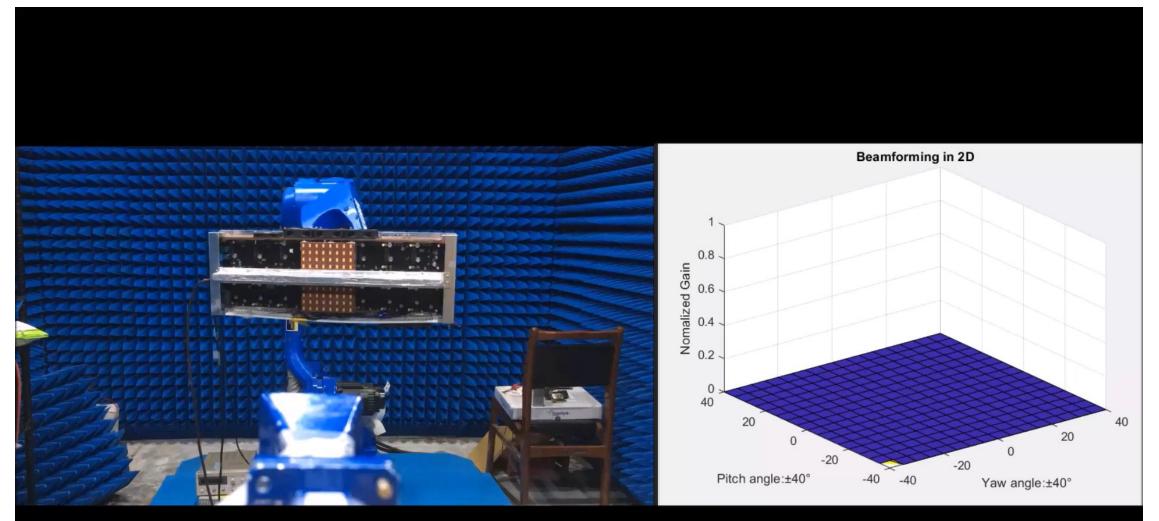
2018 prototype

The LTCC Multichip TR Modules and AiP



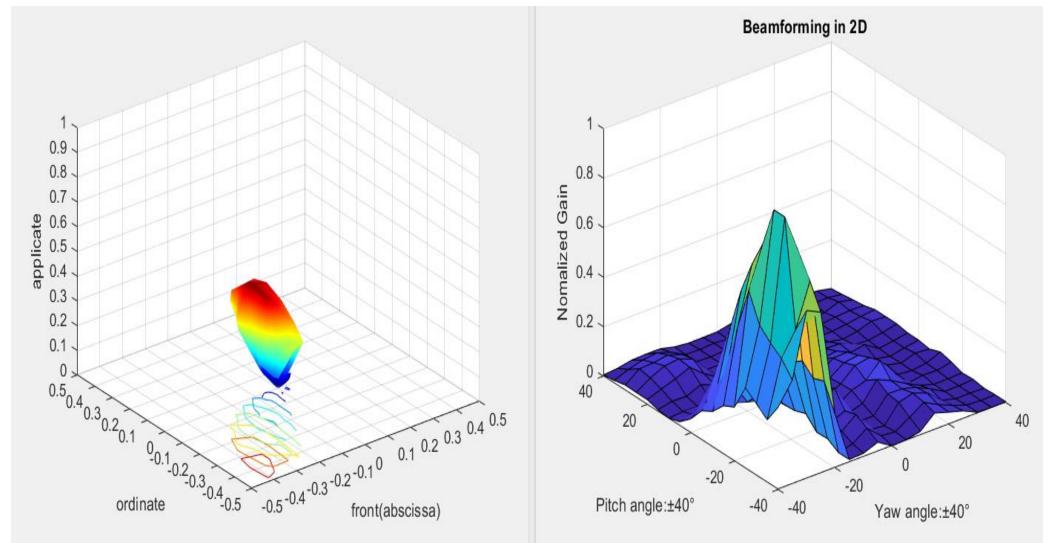
- The RF SoC can work with several GaAs and GaN frontends (LNA/PA).
- This is 2018 RD prototype, not a product.

Early 4x8 Array Pattern Measurement



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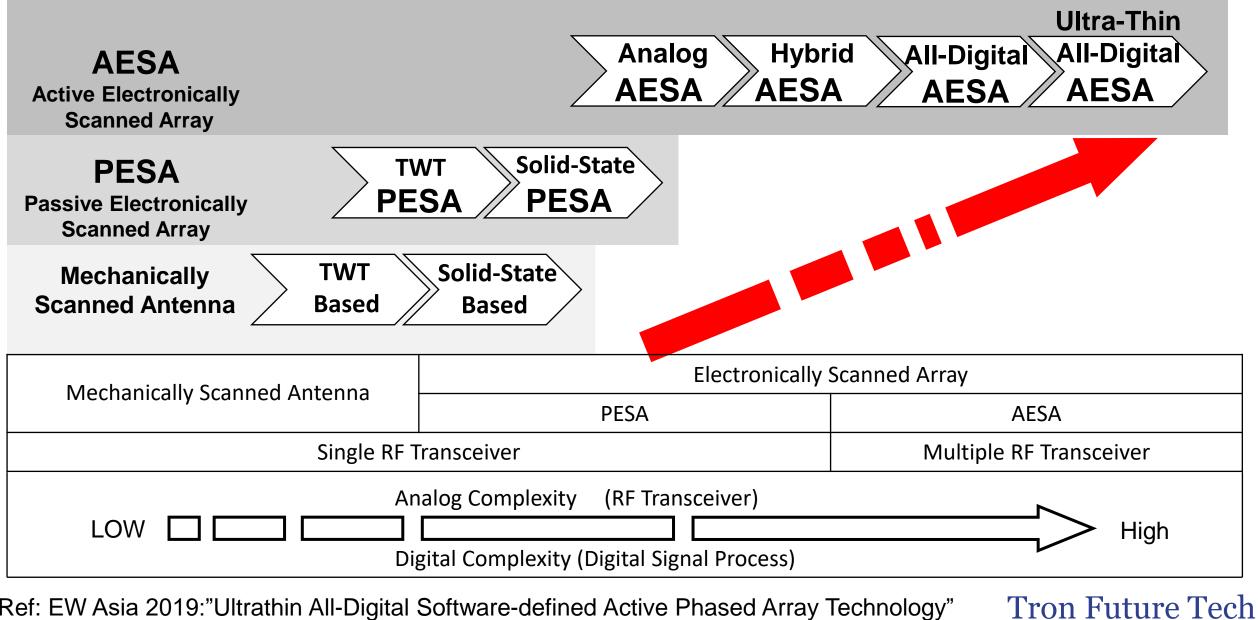
Early 4x8 Sequential Scanning Pattern



• Measured peak EIRP ~ 48 dBm with 32 CMOS only TXs.

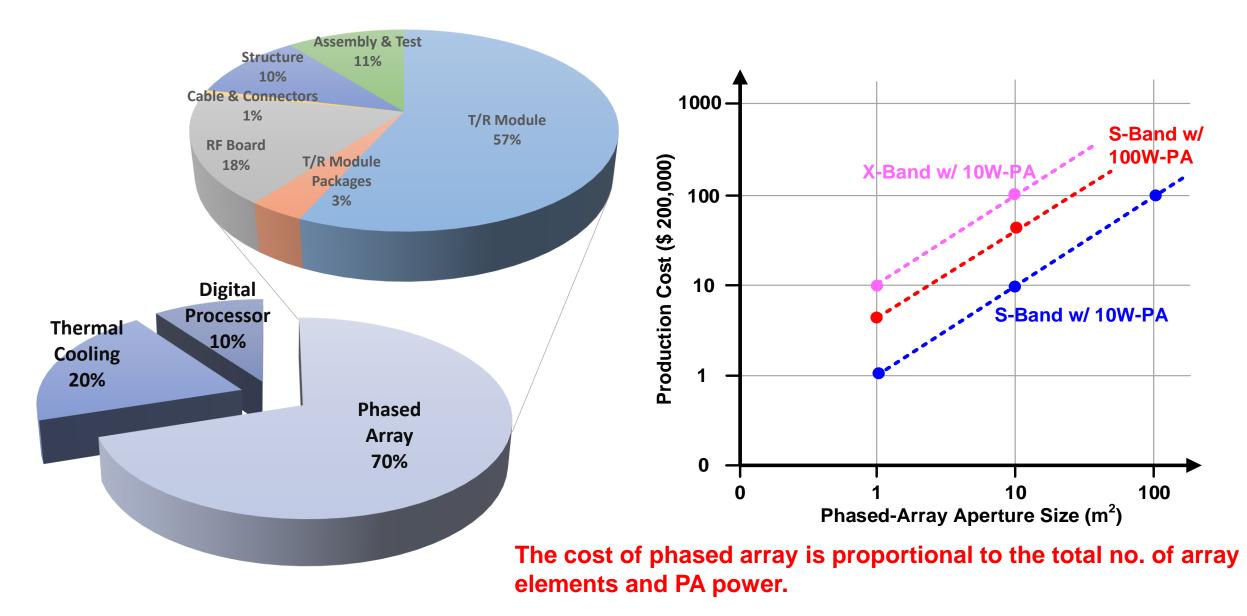
Technical Details published in IEEE Radar Conference 2019. Tron Future Tech

Wireless Scanning Technology Development



Ref: EW Asia 2019:"Ultrathin All-Digital Software-defined Active Phased Array Technology"

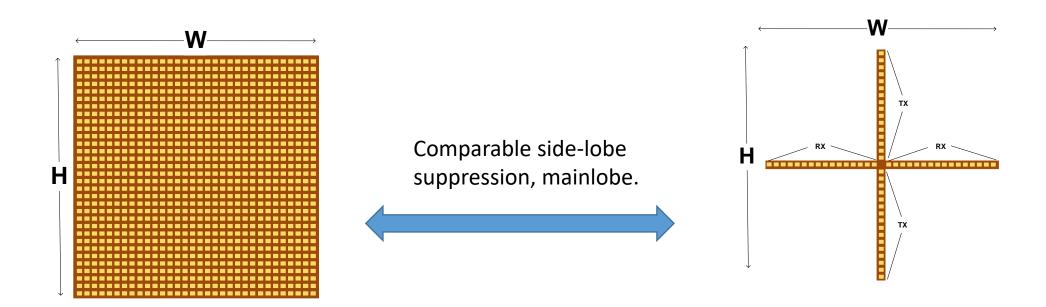
AESA Cost Issues



[Ref] Herd J.S., Conway M.D. The Evolution to Modern Phased Array Architectures. Proceedings of the IEEE, 2016, Vol. 104, No. 3, pp. 519-529.

3D AESA Cost Reduction

- Fully Populated Planar AESA.
- Orthogonal Linear Digital AESA.

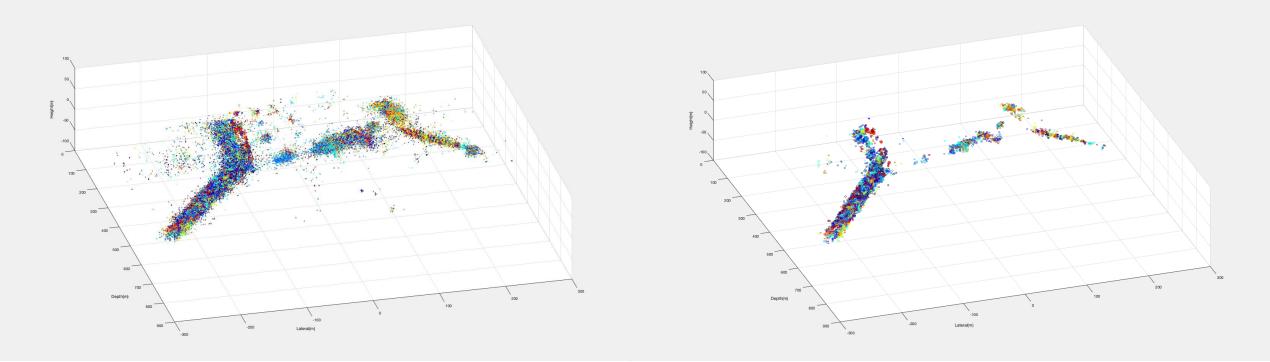


No. of Elements	W*H	H (TX), W (RX)	1024 → 32 (3% cost)	
Peak Power	$P_0 * W * H$	$\sim P_0 * (H)$	3% original power	
Antenna Gain	$\propto W * H$	$\propto W$ (RX), $\propto H$ (TX)	3% gain for RX & TX	
Max. Dwell Time	T_0	Т ₀ * Н	32 times with RX multibeam	
SNR	SNR ₀	$SNR_0 \cdot H/H^3$	1/1024 → (18% detection range)	
Cost per Area	C ₀	C ₀	Similar cost per coverage area.	ıre

An Urban Surveillance Scenario



3D Detection with 16TX, 24RX

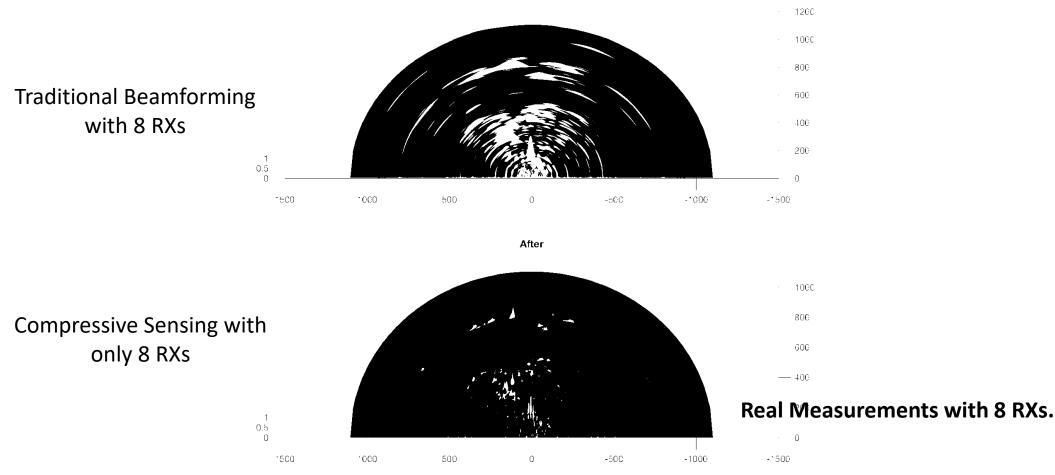


- "3D" position of an RCS target can be extracted.
 - Curvature of high-way can be precisely measured from a remote site.
- Ground surface estimation and target pattern recognition is used to identify drone from clutters(cars).
 - Target height from estimated earth surface.
 - Speed range and track properties
 - RCS Size.

10 frames, 1 Hz update Rate, 10 Sec. continuous. Each point represents a moving object.

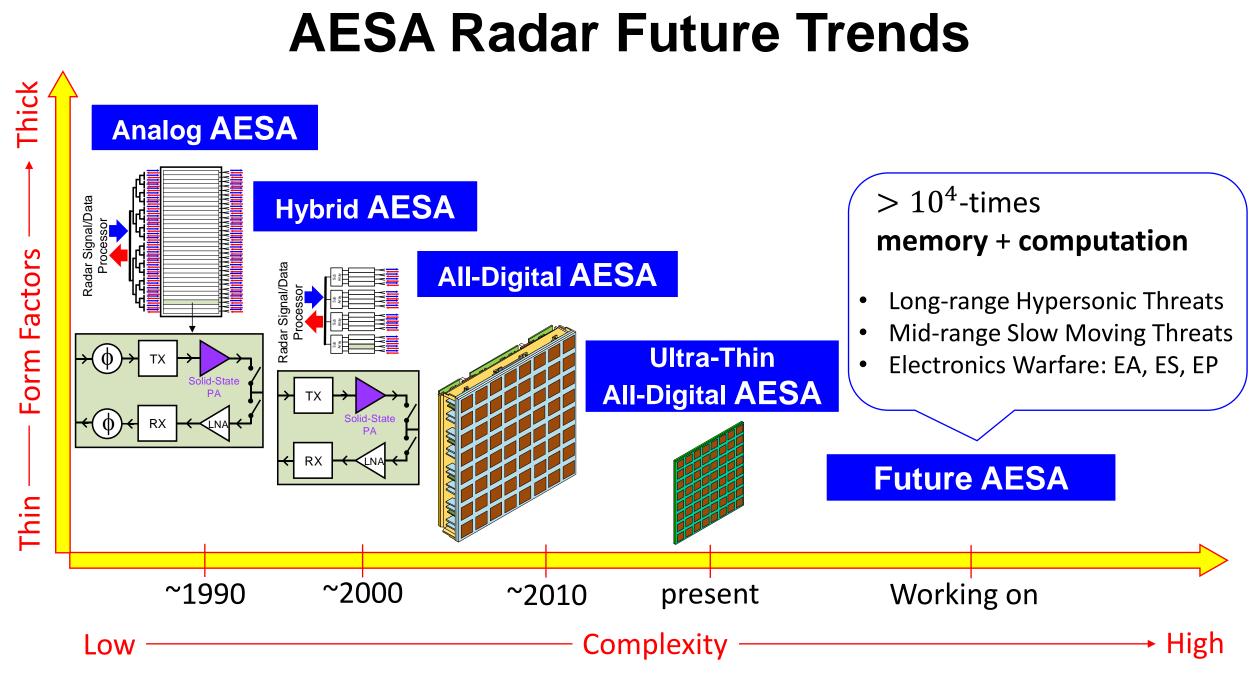
Digital AESA + massive computations

- In previous slides, digital AESA tries to mimic analog AESA. Today's CPU is 10,000 times better than CPU in 2000.
- Compressive sensing requires 10⁵ times computations compared to beamforming for 1000 RTX.



Before

• Ultra-fine spatial/velocity- resolution in the same aperture.



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Agenda

- Technology Progress Overview.
- Market Segmentation.
- Testing Challenges.



This section will be updated during presentation.

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Summary

- Technology progress enables large-aperture phased array in ultra-thin formfactor, and enhancing many existing and new applications.
- Future phased array market will be segmented into three major sectors:
 - **Digital full array:** computation intensive high performance market.
 - Digital sparse array: computation intensive low cost market
 - Hybrid array: power efficient satellite market.
- Ultrathin array testing will not only rely on Keysight's high-performance equipment's (e.g. PNA-X), array products will have extensive built-in-selftest, system-level adaptive algorithm, software-intensive system-level environment testing simulation framework, and innovative production testing mechanics to drive normalized array cost by a factor of four in the next decade.